



ISW

Docket No.: M4065.0167/P167-A
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Kevin G. Donohoe et al.

Application No.: 10/779,843

Confirmation No.: 9432

Filed: February 18, 2004

Art Unit: 1765

For: ASPECT RATIO-CONTROLLED ETCH
SELECTIVITY USING TIME
MODULATED DC BIAS VOLTAGE

Examiner: K. C. Chen

RESPONSE TO RESTRICTION REQUIREMENT

MS Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In response to the restriction requirement set forth in the Office Action mailed September 28, 2005 (Paper No. 092205), Applicants hereby elect Group III, claims 53-63 for continued examination, without traverse. Examination of the elected claims is requested.

Dated: October 17, 2005

Respectfully submitted,

By

Thomas J. D'Amico
Registration No.: 28,371
DICKSTEIN SHAPIRO MORIN &
OSHINSKY LLP
2101 L Street NW
Washington, DC 20037-1526
(202) 785-9700
Attorney for Applicant